



Quantitative Image Analysis for Radiological Image Understanding

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Message from the Guest Editors

The aim of this Special Issue is to provide researchers with a forum to present their original and disruptive research in the field of quantitative imaging for improving the understanding of radiological images and help to radiologists/physicians in the early detection (screening and early diagnosis) of diseases.

Keywords

- biomedical image and data analysis
- quantitative medical imaging
- radiological image
- pattern recognition
- machine (deep) learning
- data analysis
- artificial intelligence
- cloud computing and high-performance computing applied to precision imaging and precision medicine

Deadline for manuscript
submissions:

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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